New atomic force microscopy systems in the CharFac

**Bruker NanoIR3**
- Combines (pulsed) infrared laser spectroscopy with AFM scanning and measurement modes.
- Images chemical composition (via bond or lattice vibrations) down to unprecedented length scales (~10 nm, the tip-sample interaction zone).
- Applicable to solid matter (hard/soft) in physical/bio sciences and engineering.

**Bruker Dimension Icon**
- Handles large samples (up to 6” wafer)
- Motorized stage with digitally stored locations for rapidly moving between sites (comparison of samples or with standards; tip-state checks)
- Fully linearized X-Y-Z scanner, 12-micron Z range, ultralow noise (<20 pm rms in Z)
- Expanded functionality in force-distance mapping (data cubes) for contrasting materials and measuring physical properties